## Notice of References Cited

Application/Control No. 10/090,102	Applicant(s)/Patent Under Reexamination ZEIF, ALEX G.		
Examiner	Art Unit		
Patrick J. Assouad	2857	Page 1 of 1	

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2002/0038235 a1	03-2002	Musafia et al.	705/11
ļ .	В	US-6,539,271	03-2003	Lech et al.	700/108
	С	US-6,115,643	09-2000	Stine et al.	700/110
	D	US-2002/0077711 a1	06-2002	Nixon et al.	700/51
	Е	US-2004/0102924 a1	05-2004	Jarrell et al.	702/181
	F	US-2003/0004765 a1	01-2003	Wiegand, Bodo	705/7
	G	US-2002/0138169 a1	09-2002	Sakaguchi, Mitsuo	700/108
	Н	US-2002/0038235 a1	03-2002	Musafia et al.	705/11
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	Ÿ				
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	Ρ					
	ď					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Szabados, "Intelligent Monitoring System Used to Control Asynchronous Production Systems", IEEE, 19-20 May, 2001.
	V	Lin et al., "A PC-Based Real Time Measurement System for Factory Automation on Quality Control and Production Control", IEEE, 1989.
	w	
	x	

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.